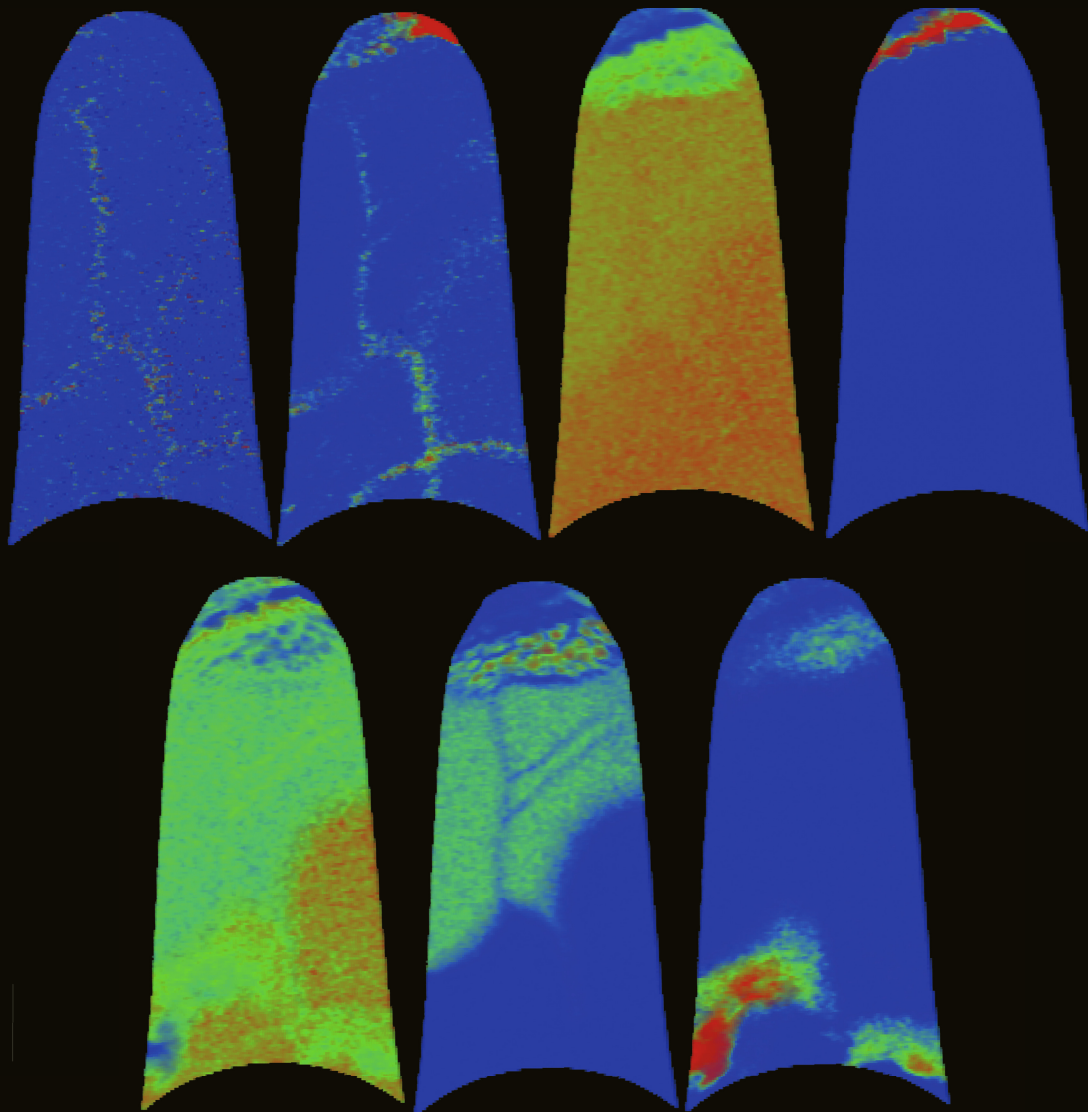


Volume 23, Number 2 April 2017

# Microscopy AND Microanalysis

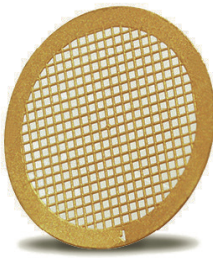


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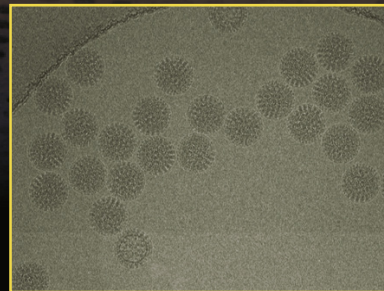
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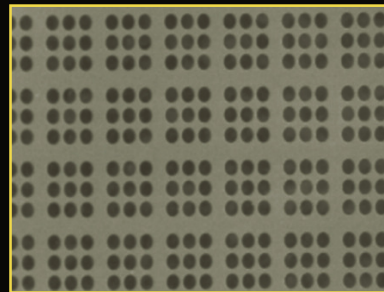
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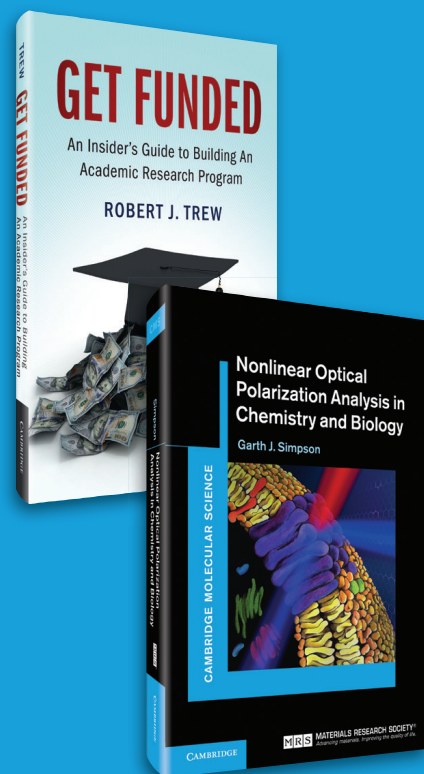
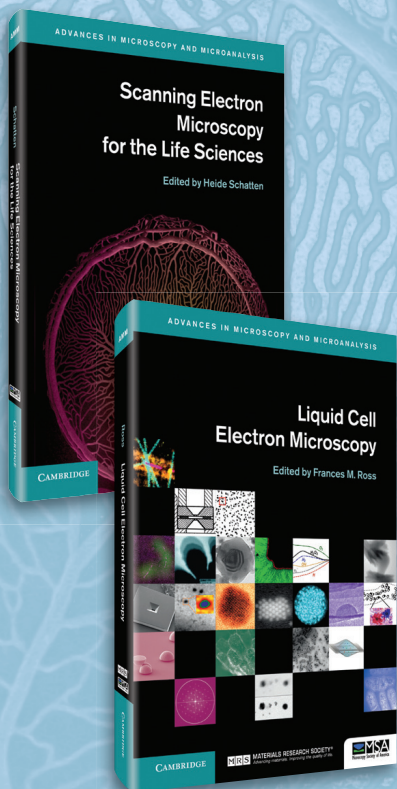
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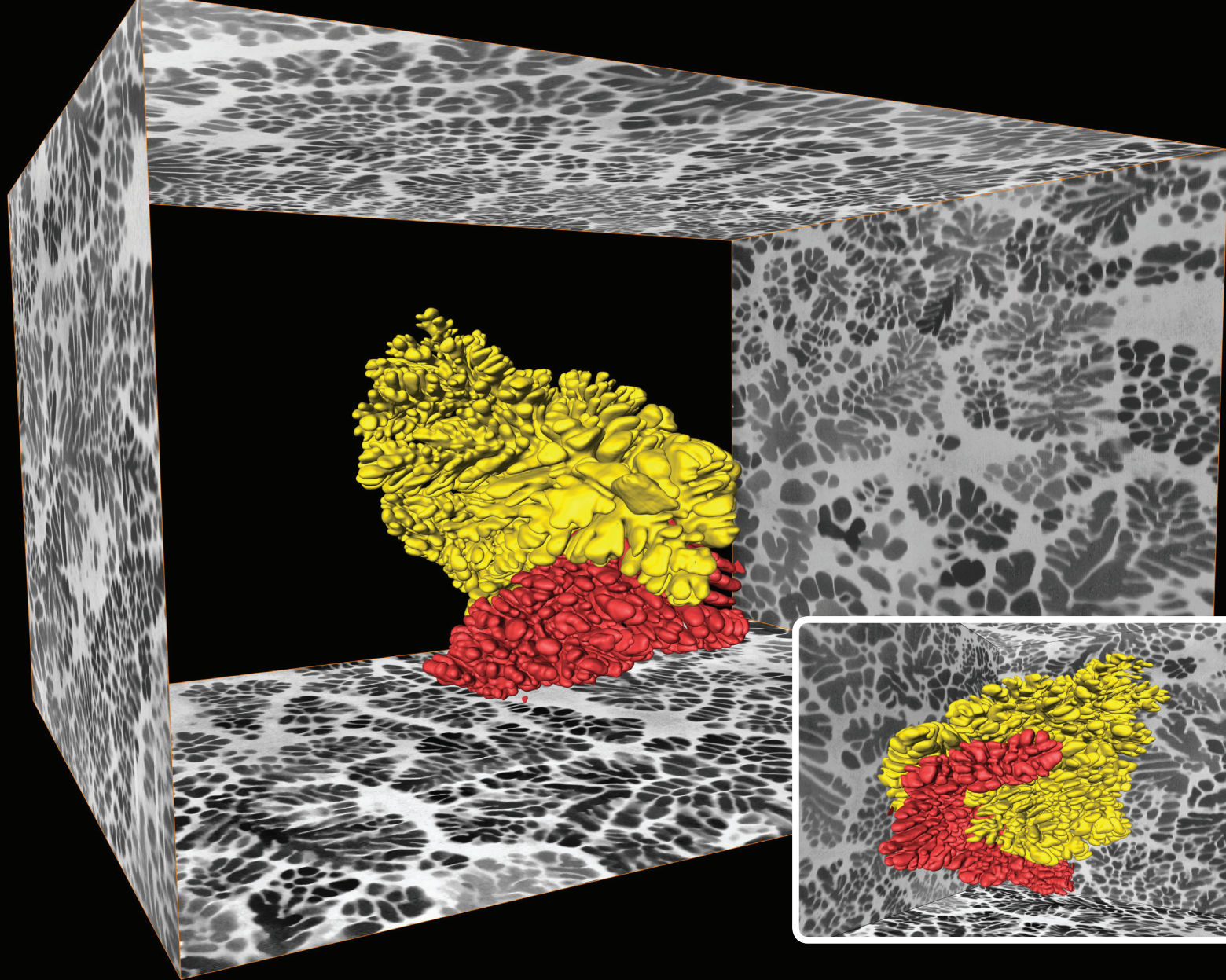
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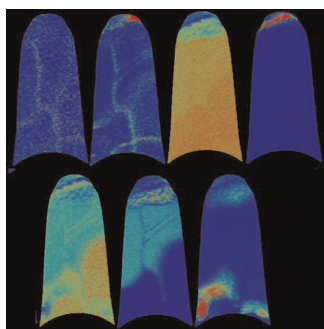
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**On the Cover:** The cover image shows atom probe tomography reconstructions of an oxide coating on a nickel-aluminum-chromium alloy which has been doped with yttrium and hafnium. In the heat maps red indicates a high, and blue a low concentration. The top row, from left to right, are yttrium, hafnium, oxygen and gold and the second row, again from left to right, are aluminum, nickel and chromium. A protective Au-coating is still present on top of the oxide. For further details, see Boll et al., pp. 396–403.

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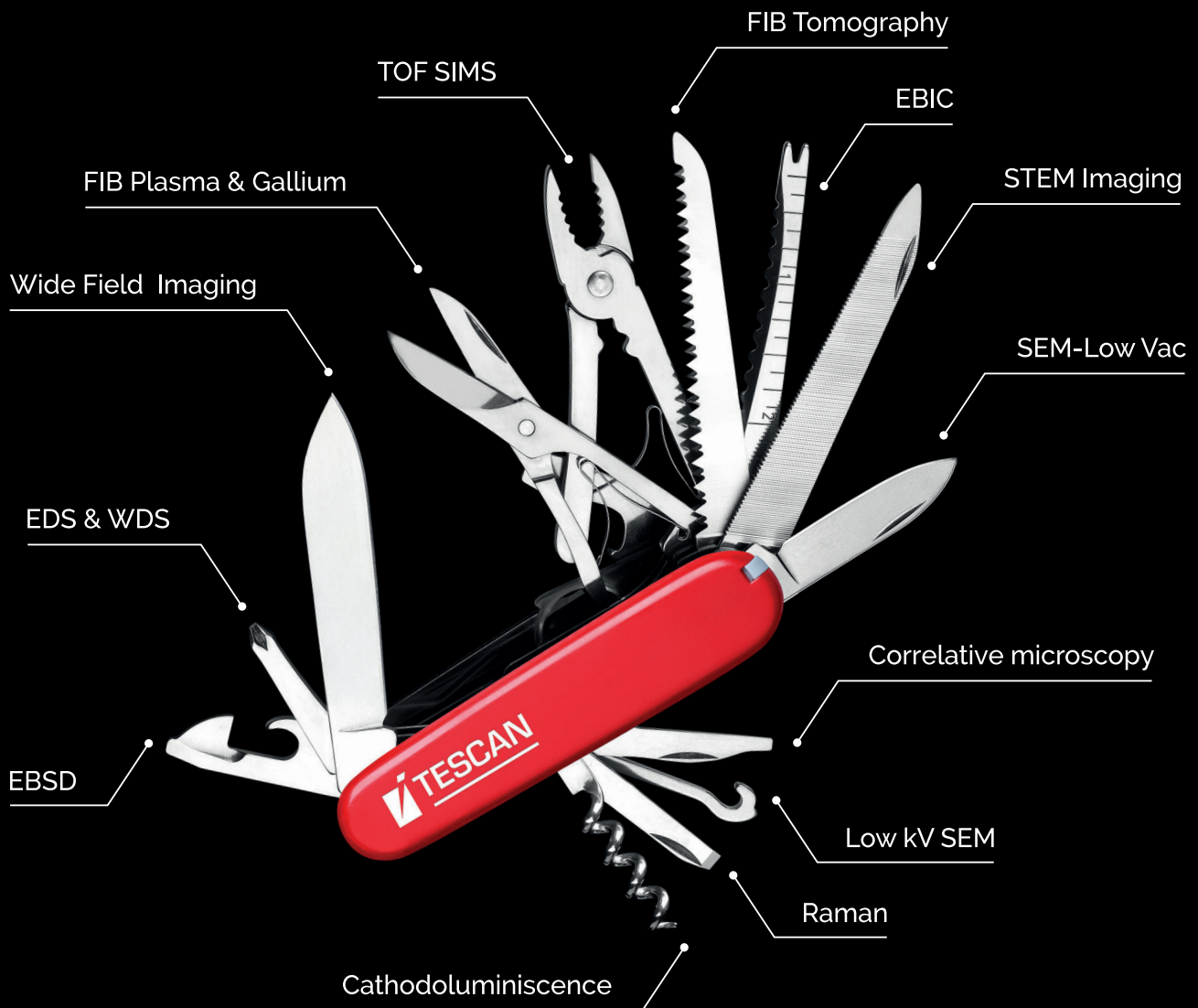
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